

23.03.2015 - 26.03.2015 – 5th Erlangen TEM-School 2015

Location CENEM, Cauerstraße 6, Erlangen

This year young researchers interested in transmission electron microscopy (TEM) are again invited to participate in the Erlangen TEM school from 23rd-26th March 2015, organized by Prof. Erdmann Spiecker and his team at the Center for Nanoanalysis and Electron Microscopy (CENEM) of the University of Erlangen-Nürnberg. The school offers an excellent opportunity to become familiar with the theory and application of different electron microscopy techniques: electron microscopy sample preparation (conventional and FIB), electron diffraction, conventional TEM, high-resolution and analytical TEM. CENEM is equipped with CM30, CM300 and double-corrected TITAN³ Themis TEMs as well as Dual-Beam FIB Helios NanoLab660. We intend to initiate discussions regarding the possibility of applying these techniques in the research projects of the participants. The participants are therefore requested to complement their application with an abstract of about 150 words highlighting their research interests in the context of electron microscopy. Daily program of the TEM School typically comprises a lecture on the theory and application of TEM methods followed by practical sessions in the sample preparation and TEM laboratories of the CENEM. Therefore the number of participants is limited to 15 researchers.

Application deadline: February 15th 2015

Decision about participation by February 20th 2015

Fee: 400 €; Members of DGE, EAM and FAU exempt from charge

Please send your application and abstract to Nadine.Schrenker@fau.de